

Thermal Stability and Crystallization Processes of $\text{Pd}_{78}\text{Au}_4\text{Si}_{18}$ Thin Films Visualized via In Situ TEM

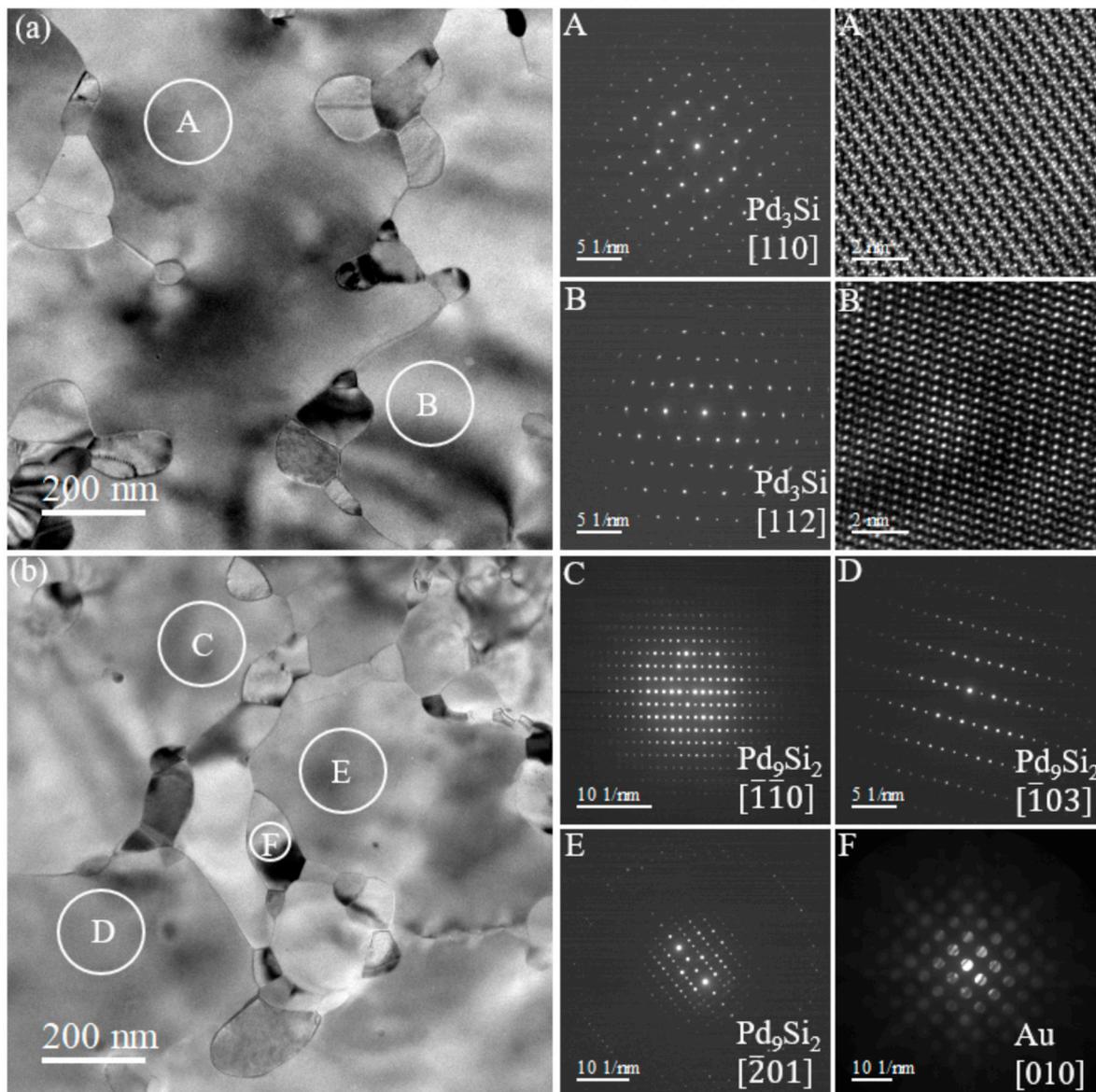


Figure S1. The final products of heating treatment of $\text{Pd}_{78}\text{Au}_4\text{Si}_{18}$ thin film at around 900 K. (a) Pd_3Si intermetallic phase and the corresponding SAED patterns and HRTEM lattice images of the regions marked by A and B. (b) Pd_9Si_2 intermetallic phase and the SAED patterns and HRTEM lattice images of the regions marked by C, D, E, and F.

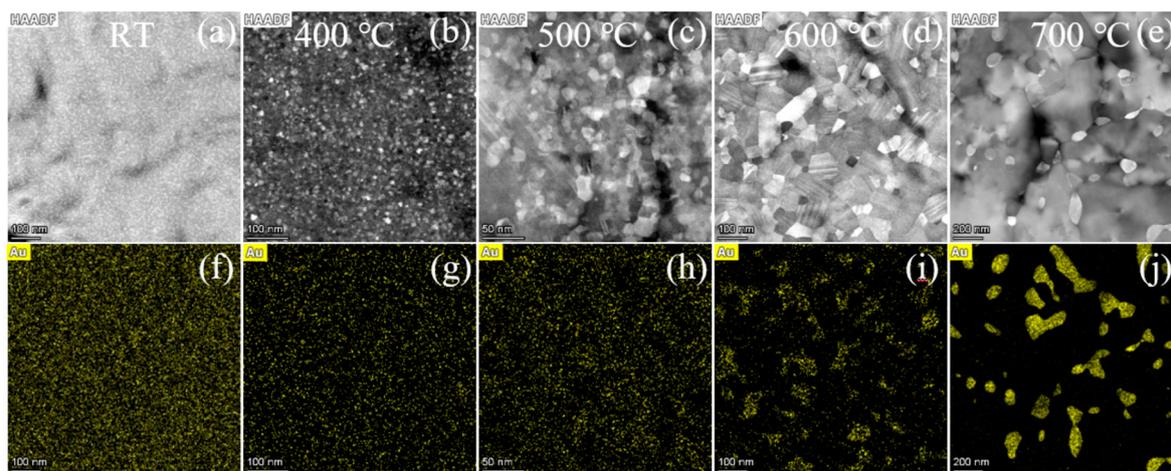


Figure S2. HAADF-STEM images (a–e) and EDXS mappings (f–j) of the Pd₇₈Au₄Si₁₈ thin film at different temperatures.